Supporting Information

Shape Control in Silver Metal Nanoparticle Construction Using Dumb-bell Dendrimers

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Transmission electron microscopy (TEM) measurements were carried out on a JEOL 2000FX microscope operating at an acceleration voltage of 80 kV. X-ray powder diffraction (XRPD) experiments were performed using a Siemens D-5000 diffractometer. It was equipped with a step scanner and a 1.2 kW cobalt tube ($\lambda = 1.78897 \text{ Å}$) coupled to a silicon detector. The diffraction patterns were acquired in the reflection mode, for 20 values ranging from 4 to 90 degrees. The X-ray beam was fixed while the sample holder and the detector were moved to scan the solids. UV-Vis measurements were recorded in water on a Hewlett Packard 8453 with a resolution of 2 nm.
XRPD patterns for generations 1 (A), 2 (B) and 3 (C) templated silver particles.
Size distribution graphs for generation 1 (A), 2 (B) and 3 (C) templated silver particles